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Preliminary results on TPA studies on LGADs at ELI Beamline

Presented by Gordana Medin

Full list of authors is on the next page

Collaboration/People & Institutions

- ❑ **ELI Beamline, CZ** – RP4 group (Application in Molecular, Bio-medical and Material Science) and BIS group
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 - ❑ Jiří Kroll, Michal Tomášek
- ❑ **University of Montenegro**
 - ❑ Gordana Medin
- ❑ **JSI**
 - ❑ Gregor Kramberger
- ❑ **INFN Torino**
 - ❑ Nicolo Cartiglia, Valentina Sola

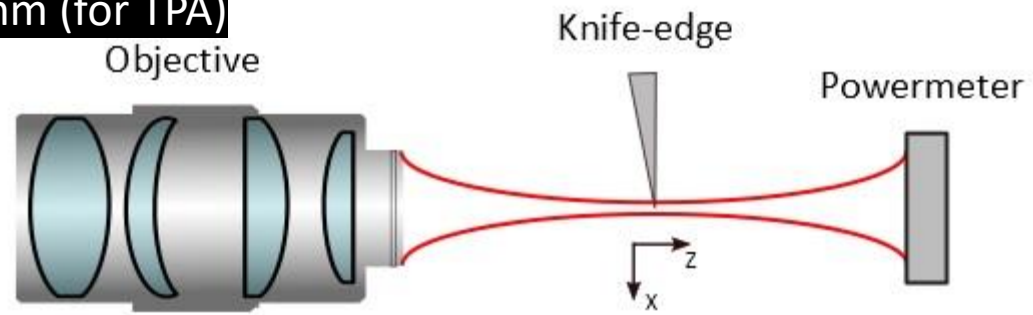
OUTLINE

- ❑ **Gaussian Beam Optics**
- ❑ **Quadratic relation between collected signal (in Si) and laser power**
- ❑ **Charge Generation via TPA (LGAD & PIN)**
- ❑ **Z-scan (LGAD & PIN)**
- ❑ **First measurements with TPA (LGAD & PIN)**

Beam profile and parameters at 1550 nm (for TPA)

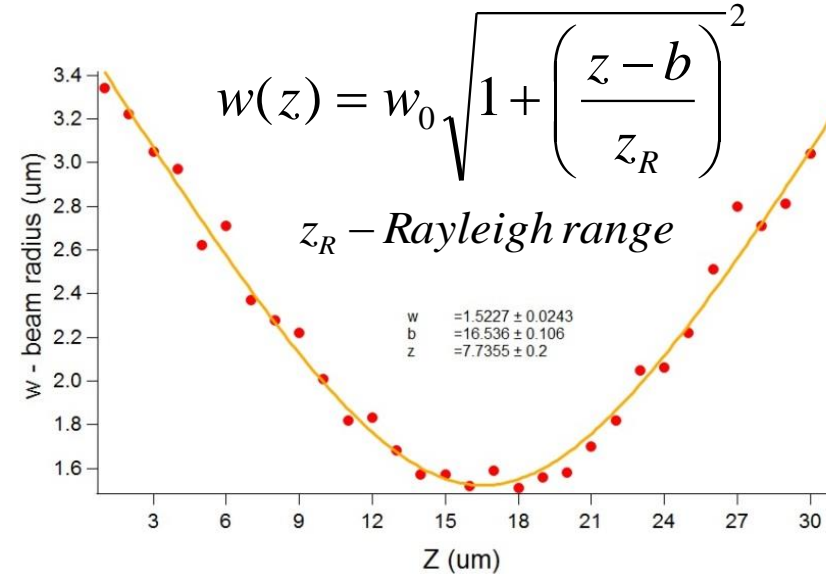
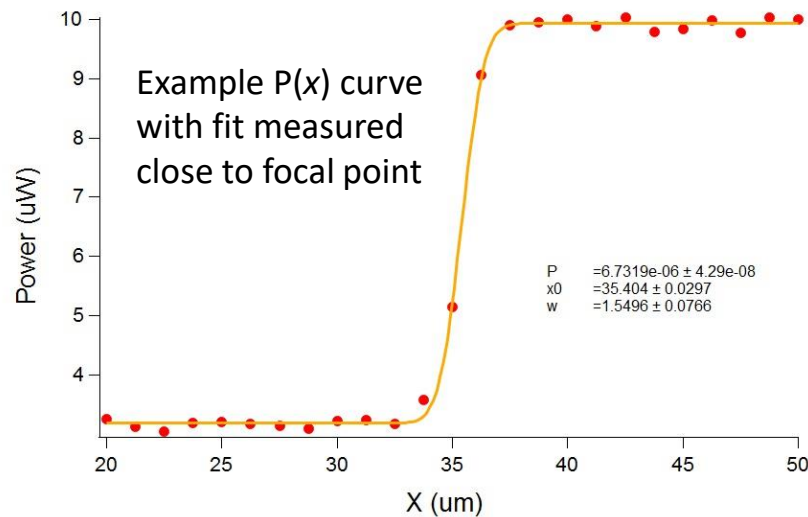
$$P_{measured} = \frac{P}{2} \left[1 - \operatorname{erf} \left(\frac{\sqrt{2}(x - x_0)}{w} \right) \right]$$

$w - 1/e^2$ radius Gaussian beam



100X Mitutoyo Plan Apo NIR HR
Infinity Corrected Objective
 $\lambda = 1550 \text{ nm}$

1. $P(x)$ measured for series of Z points around focal point
2. $w(Z)$ obtained by fitting for every Z
3. w_0 and Z_R obtained by fitting $w(Z)$ curve



Final parameters (in air):

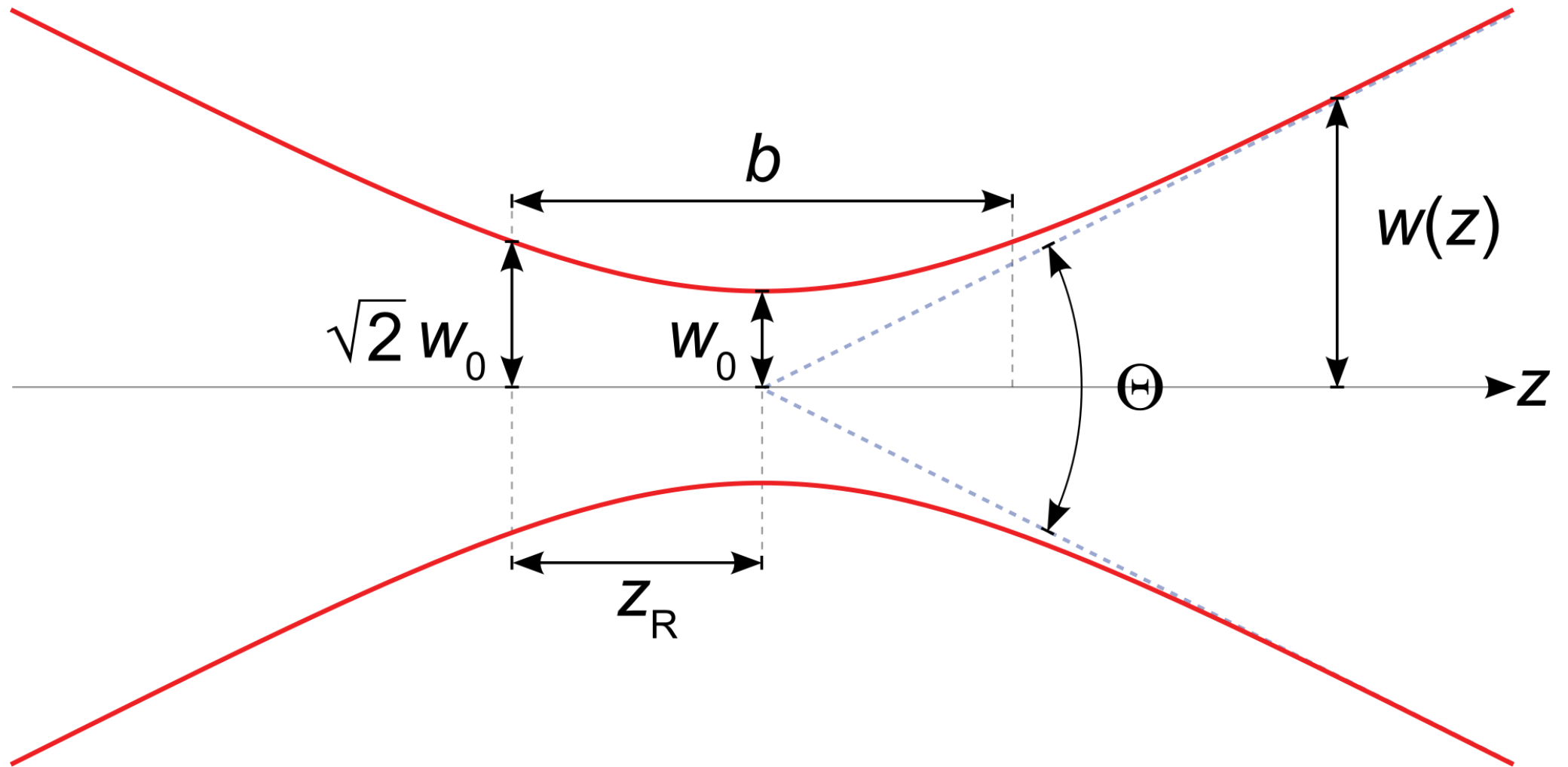
$$w_0 = 1.52 \mu\text{m}$$

$$Z_R = 7.74 \mu\text{m}$$

In Si : refractive index correction needed

$$n = 3.48 \text{ at } 1550 \text{ nm}$$

$NA = 0.31$ (nominal $NA = 0.7$ but probably not valid for focal point)



At ELI Beamline final parameters (in air): $w_0 = 1.52 \mu\text{m}$. $Z_R = 7.74 \mu\text{m}$

For comparison: TCT-TPA at CERN: $w_0 = 1.7 \mu\text{m}$, $Z_R = 17 \mu\text{m}$

JSI Board

stay stick

**Four sensors on
one 1-channel
board**

**WF25, PIN25
WF36, PIN36**

**Sensor
mounting/Wire
Bonding**

**INFN Boad
INFN UFSD-W1 sensor**

2x4 area

Only one pad used

Proof of 2PA in W25 PIN Indication to 3PA & Plasma contribution

Signal \sim Irradiance²

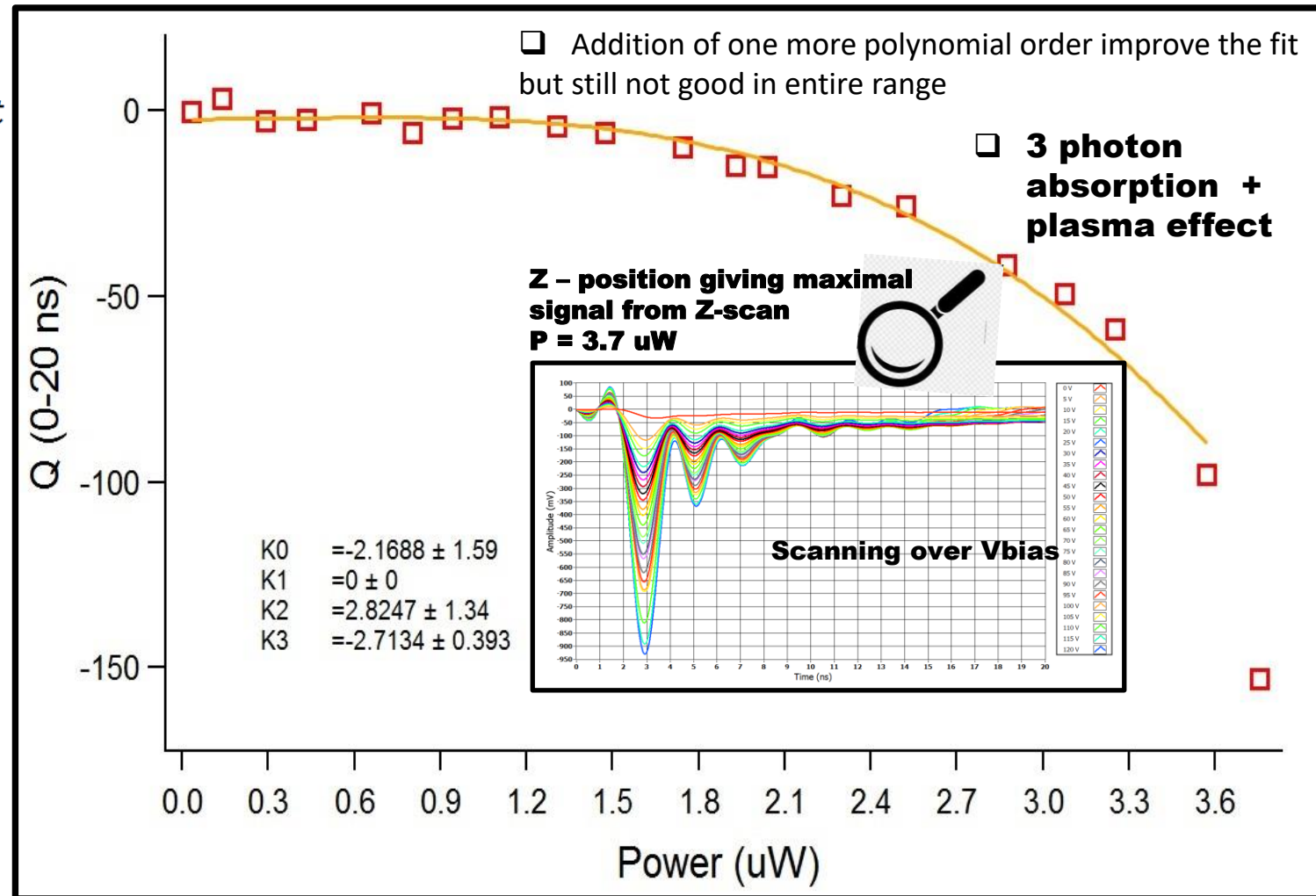
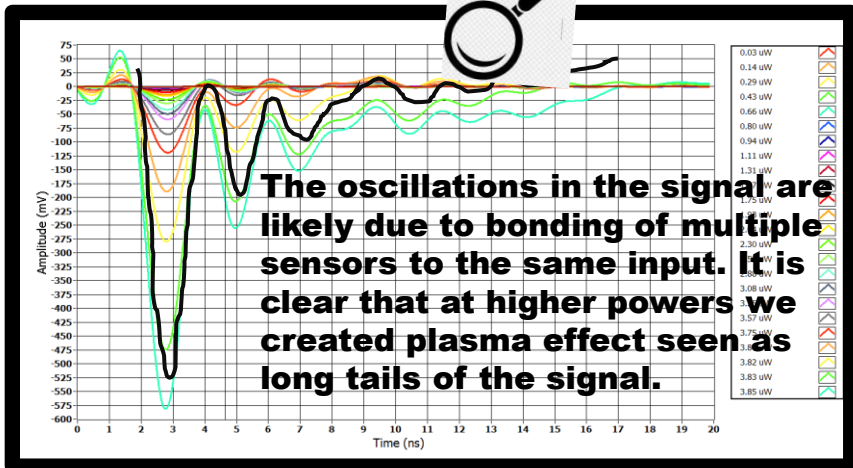
$$\frac{dN(r,z)}{dt} = \frac{\beta I^2(r,z)}{2\hbar\omega} \rightarrow \Delta N(r,z) = \frac{\beta I^2(r,z)}{2\hbar\omega} \Delta t$$

$Q \propto N$ $P \propto I$

□ Quadratic relation between collected signal (in Si) and laser power

Z – position giving maximal signal from Z-scan
V_{bias} = -100 V

Scanning over laser power



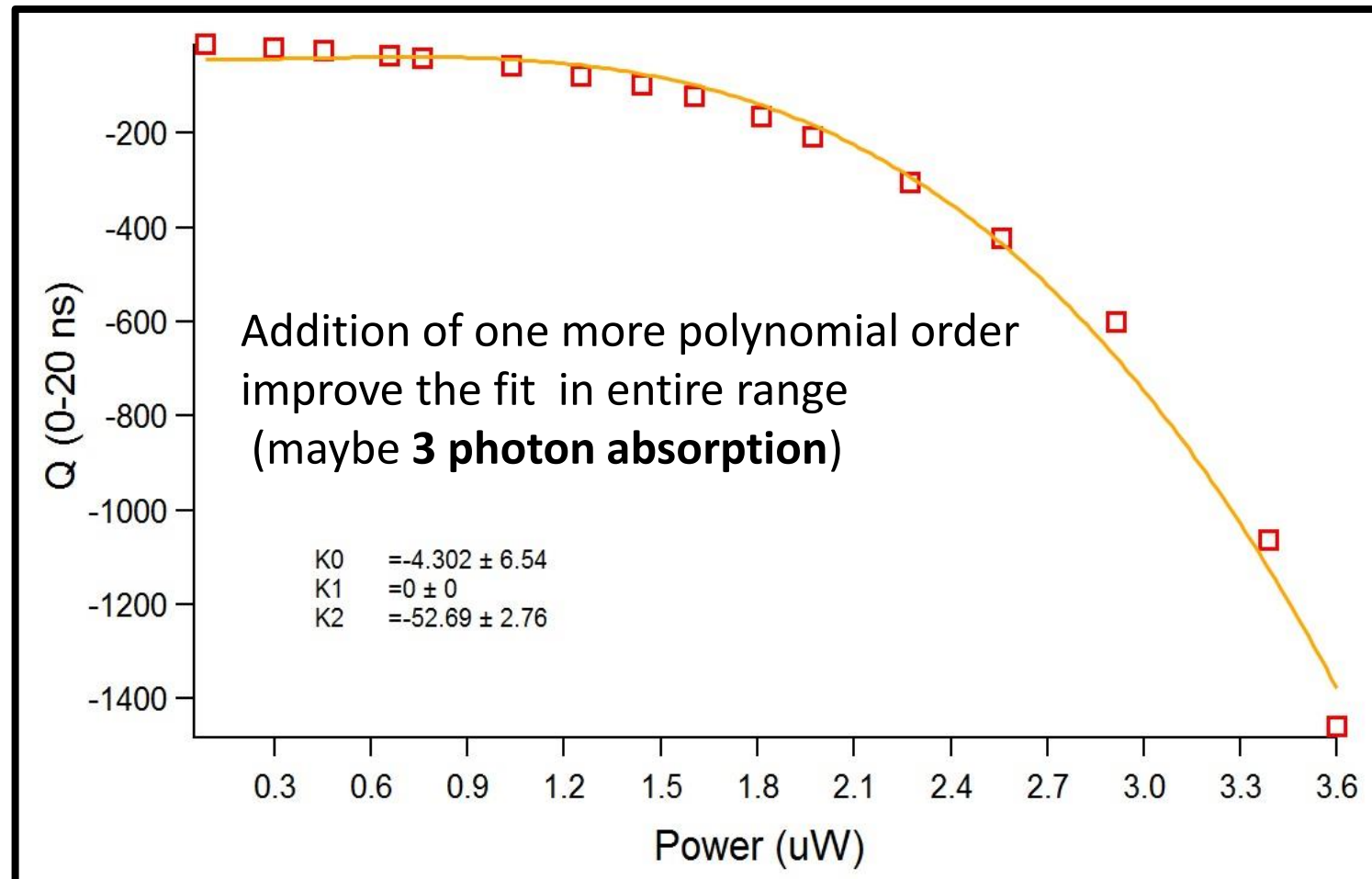
Proof of TPA LGAD WF25 (HPK-P2)

Signal \sim Irradiance²

$$\frac{dN(r, z)}{dt} = \frac{\beta I^2(r, z)}{2\hbar\omega} \quad \rightarrow \quad \Delta N(r, z) = \frac{\beta I^2(r, z)}{2\hbar\omega} \Delta t$$

$Q \propto N$ $P \propto I$

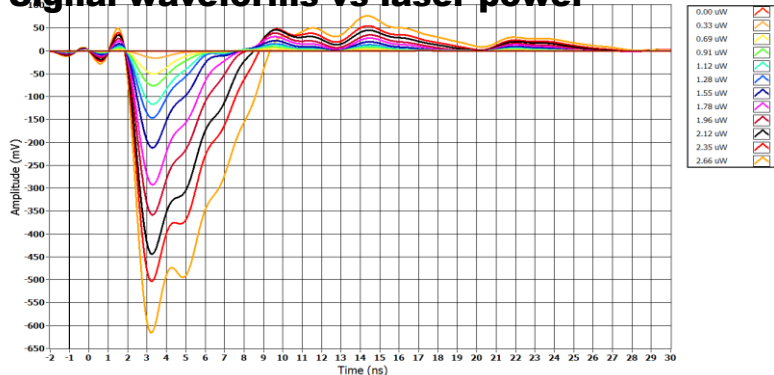
- ❑ Quadratic relation between collected signal (in Si) and laser power



Proof of TPA LGAD INFN: UFSD -W1

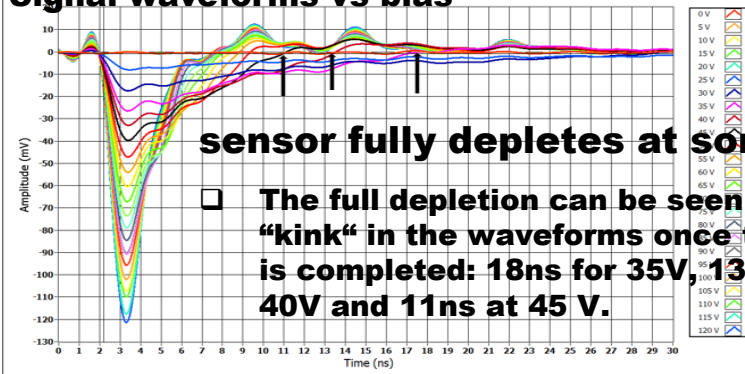
Z – position giving maximal signal from Z-scan
 $V_{bias} = -100 V$

Signal waveforms vs laser power



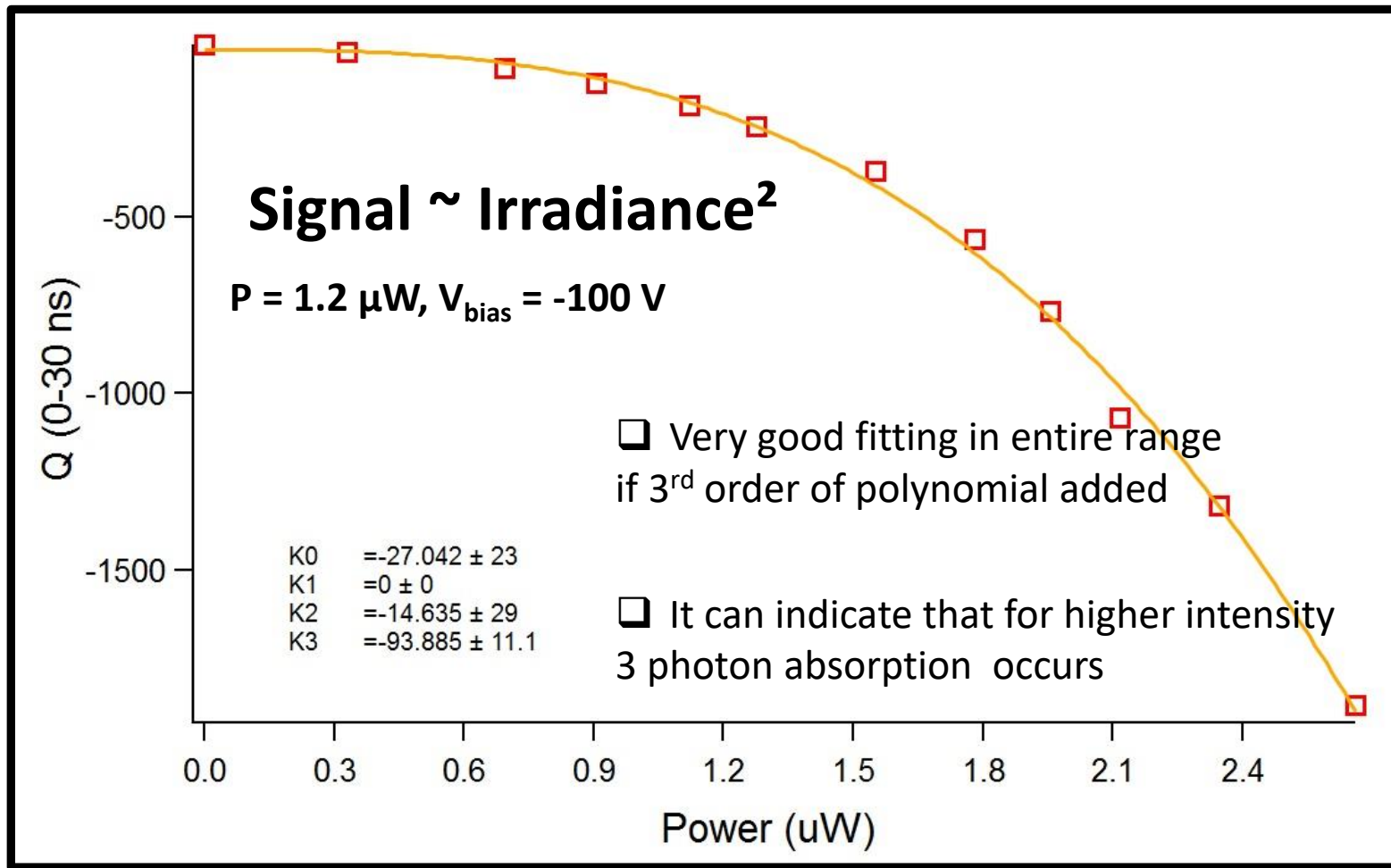
Z – position giving maximal signal from Z-scan
 $P = 1.1 \mu W$

Signal waveforms vs bias

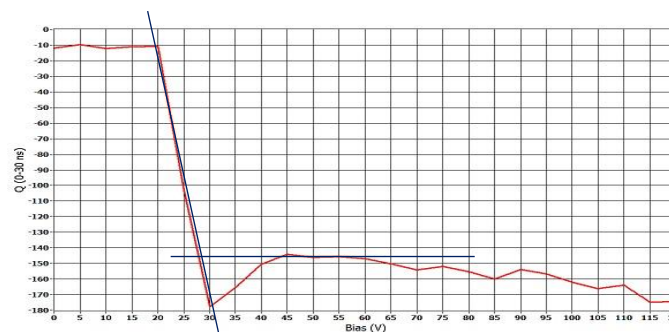


sensor fully depletes at some 35-40V

□ The full depletion can be seen as the “kink” in the waveforms once the drift is completed: 18ns for 35V, 13.5 ns at 40V and 11ns at 45 V.



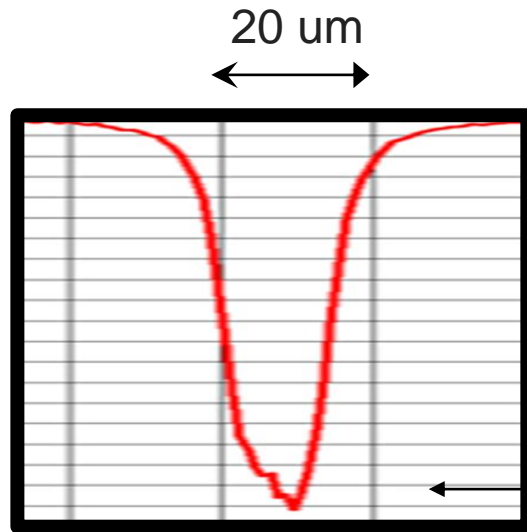
Q-V plot



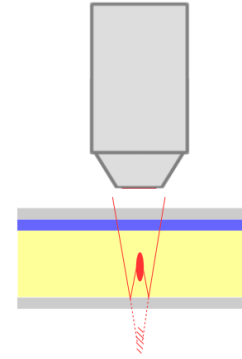
Proof of TPA PIN_{ref}(WF25)

Z-Scan

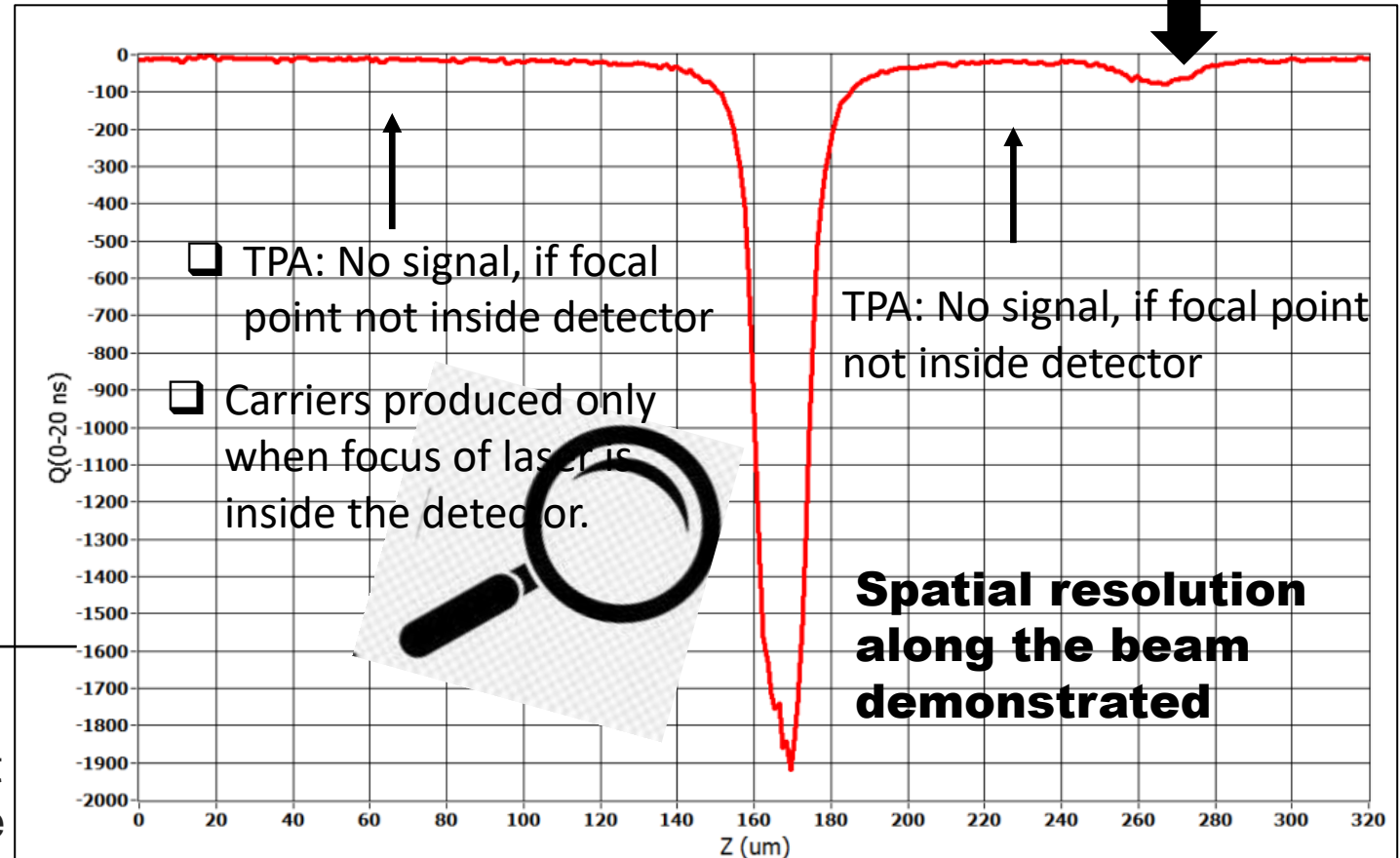
$P = 3.2 \text{ uW}$, $V_{\text{bias}} = -100 \text{ V}$



- FWHM is ~14-15 um which taking into account refractive index gives you ~50 um, which is the thickness of devices



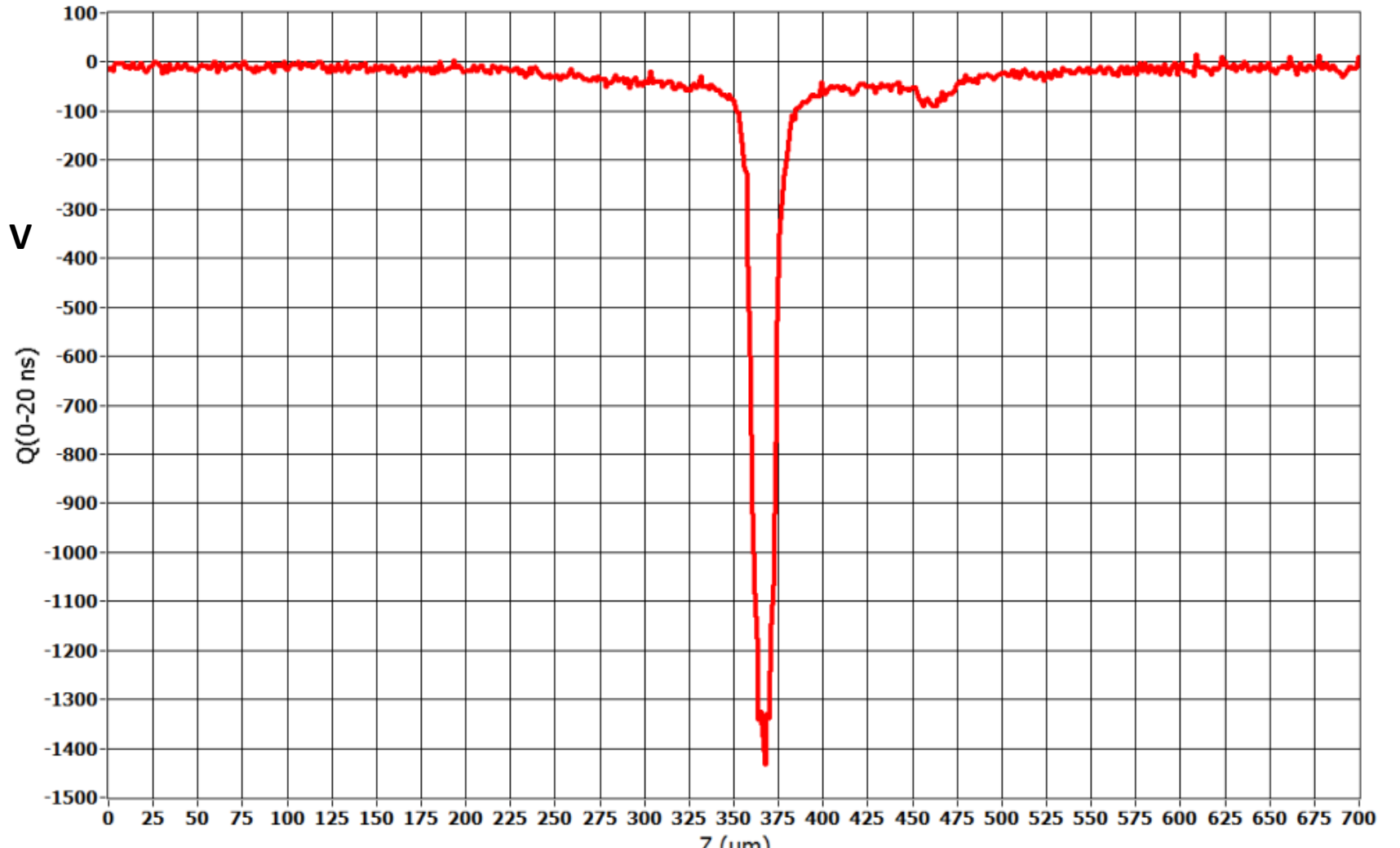
The second peak Z2 is very likely coming from the reflection of the light from the bottom of the sensor. The sensor is comprised from: 50um sensitive bulk on the silicon substrate wafer which is metallized at the bottom. It could happen that at right position the reflected beam causes TPA in the active region



Proof of TPA LGAD WF25 (HPK-P2)

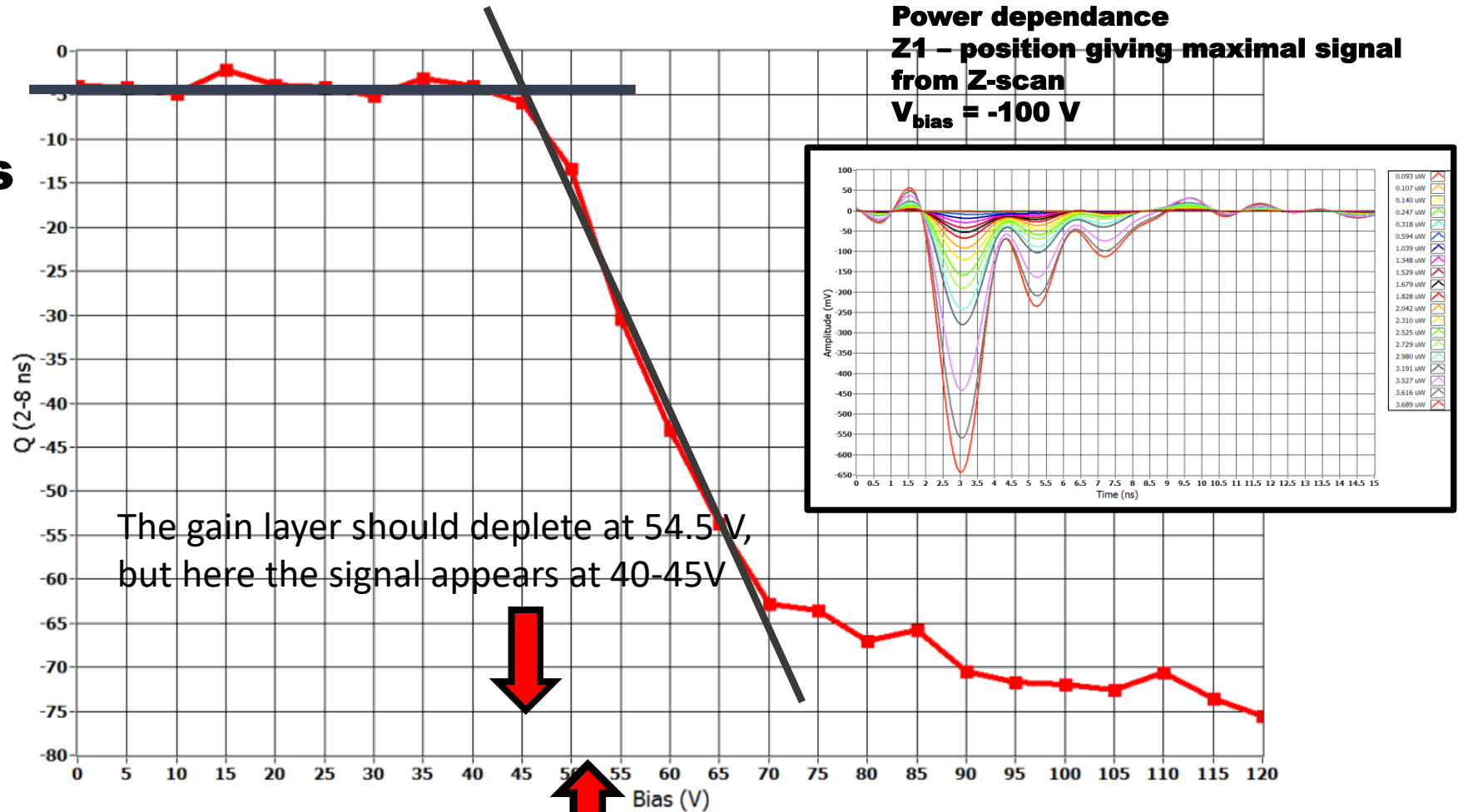
Z-Scan

$P = 3.7 \mu\text{W}$, $V_{\text{bias}} = -100 \text{ V}$

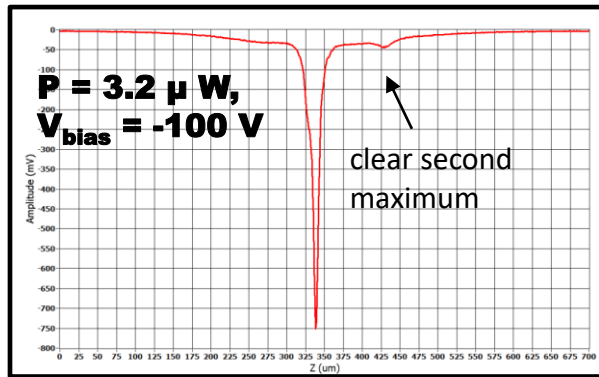


First characterisation of LGAD with TPA: Determination of gain layer depletion voltage (V_{gl})

LGAD W36
Q vs. HV Bias
P = 3.2 μ W



Z-scan (front to back) on LGAD W36

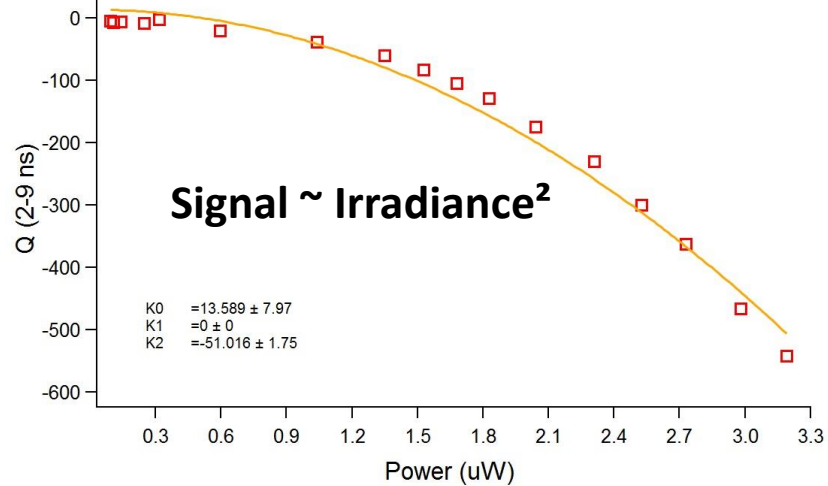


First/preliminary characterisation of PIN with TPA: Vfd

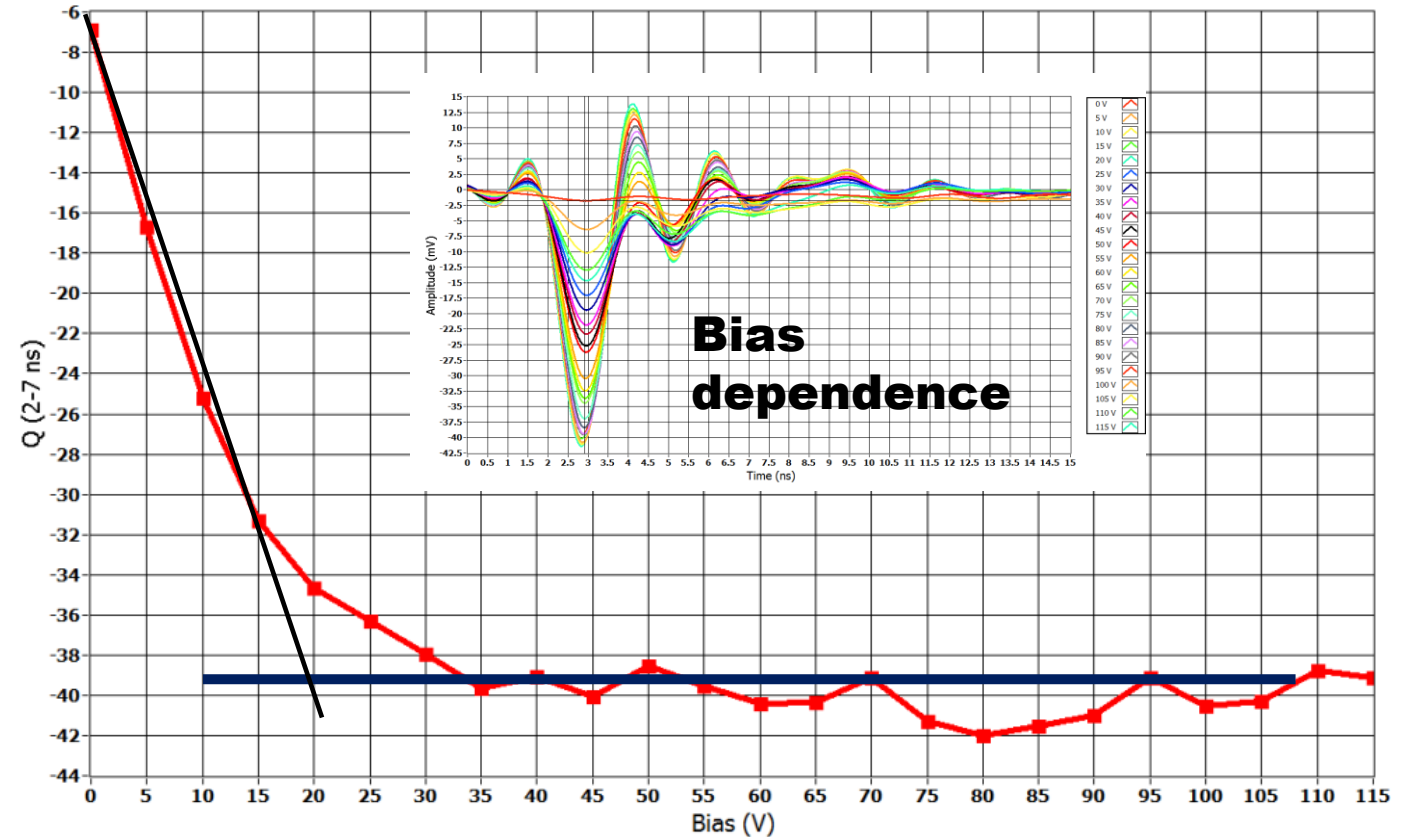
Z – position giving maximal signal from Z-scan

P = 70 nW

PIN36



Q vs. HV Bias



Conclusion

- ❑ **The first in the world compact and comprehensive fs-TCT which will have both, TCT-SPA and TCT-TPA is under commissioning at ELI Beamlines**
- ❑ **Uniqueness of set up: both, standard TCT at 800 nm but with fs-laser and also 3D scanning of sensor with TPA at 1550 nm.**
- ❑ **The excellent beam parameters achieved: $w_0 = 1.52 \mu\text{m}$. $Z_R = 7.74 \mu\text{m}$**
- ❑ **TPA process in a diode (top injection) is demonstrated.**
- ❑ **First/preliminary characterisation with TPA: gain layer depletion voltage and foot voltage in LGAD.**
- ❑ **We are still developing some parts of the system: DAQ, cooling**
- ❑ **Study on sensors just with 2nd amp and without timing boards under discussion (we have quite large signal in LGAD and it would be easier to achieve lower temperature)**

Acknowledgment

Huge thanks to Mateusz Rebarz, Kamil Kropielniczki and Jiří Kroll.

Thank to all involved.